

Notice of References Cited	Application/Control No. 10/709,446		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Matthew G. Kayrish		Art Unit 2653	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,799,122	01-1989	Tanaka et al.	360/133
*	B	US-5,883,870	03-1999	Akiba et al.	720/602
*	C	US-2004/0223447	11-2004	Tanaka et al.	369/292
*	D	US-2002/0018426	02-2002	Minase, Minoru	369/75.2
*	E	US-6,731,580	05-2004	Sato et al.	720/655
*	F	US-5,388,094	02-1995	Park, Joong-Je	720/710
*	G	US-4,497,002	01-1985	von der Heide et al.	369/268
*	H	US-4,331,989	05-1982	Viskochil, Stephen R.	360/99.08
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004227714 A	08-2004	Japan	KAMIYAMA et al.	G11B 17/04
	O	JP 2005182905 A	07-2005	Japan	ONO et al.	G11B 19/22
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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